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O.I.P.E.

PATENT DATE

SCANNED AC 2 Q.A. AA

APPLICATION NO. 09/942213	CONT/PRIOR F	CLASS 438 782	SUBCLASS 145	ART UNIT 2812 2813	EXAMINER J Strega
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APPLICANTS

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Kenji Watanabe
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Method and apparatus for inspecting a semiconductor device

TITLE

PTO-2040
12/89

ORIGINAL

CROSS REFERENCE(S)

CLASS

SUBCLASS

CLASS

SUBCLASS (ONE SUBCLASS PER BLOCK)

INTERNATIONAL CLASSIFICATION

☐ Continued on Issue Slip Inside File Jacket

**TERMINAL
DISCLAIMER**

DRAWINGS

Sheets Drwg.

Figs. Drwg.

Print Fig.

CLAIMS ALLOWED

Total Claims

Print Claim for O.G.

☐ The term of this patent subsequent to _____ (date) has been disclaimed.

☐ The term of this patent shall not extend beyond the expiration date of U.S. Patent. No. _____

NOTICE OF ALLOWANCE MAILED

ISSUE FEE

Amount Due

Date Paid

☐ The terminal ____ months of this patent have been disclaimed.

(Legal Instruments Examiner)

(Date)

ISSUE BATCH NUMBER

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(FACE)